

CERTIFICATE OF ANALYSIS

ERM[®]-EB316

AlSi12

Certified Values		
	Certified value ¹⁾	Uncertainty ²⁾
Element	Mass fraction in %	
Si	11.98	0.20
Fe	0.1054	0.0021
Cu	0.0297	0.0008
Mn	0.204	0.004
Mg	0.045	0.004
Ni	0.0235	0.0011
Zn	0.0611	0.0012
Ti	0.0790	0.0015
Element	Mass fraction in mg/kg	
Cr	59.3	2.6
Be	2.95	0.17
Bi	140	7
Cd	20.8	1.5
Ga	105	5
Pb	87	7
Sr	260	7
V	98	7
Zr	32.8	0.7
¹⁾ Unweighted mean value of the means of accepted sets of data, each set being obtained in a different laboratory and/or with a different method of measurement. The values are traceable to the SI (Système International d'Unités) via calibration using pure metals or substances of known stoichiometry. ²⁾ Estimated expanded uncertainty <i>U</i> with a coverage factor of <i>k</i> =2, corresponding to a level of confidence of approx. 95 %, as defined in the Guide to the expression of uncertainty in measurement, ISO, 1993.		

This certificate is valid until 09/2059; this validity may be extended as further evidence of stability becomes available.

DESCRIPTION OF THE SAMPLE

The Reference Material is available in the form of discs (50 mm diameter and 30 mm height). It is intended for establishing and checking the calibration of optical emission and X-ray spectrometers (excluding micro-analysis) for the analysis of samples of similar materials.

NOTE

European Reference Material ERM[®]-EB316 was produced and certified under the responsibility of Federal Institute for Materials Research and Testing (BAM) in cooperation with the Committee of Chemists of the GDMB, Gesellschaft für Bergbau, Metallurgie, Rohstoff- und Umwelttechnik according to the principles laid down in the technical guidelines of the European Reference Materials[®] co-operation agreement between BAM-LGC-IRMM. Information on these guidelines is available on the Internet (<http://www.erm-crm.org>).

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Indicative Values ¹⁾		
	Indicative value ²⁾	Uncertainty ³⁾
Element	Mass fraction in mg/kg	
Ag	183	10
Ca	11.3	1.4
Hg	35	7
Sb	56	5
Sn	106	11
¹⁾ Values were not certified, but given as indicative values, when the number of accepted data sets was considered to be too low (< 5) and/or when the uncertainty from the inter-laboratory certification was considerably larger than the expected range. ²⁾ Unweighted mean value of the means of accepted sets of data, each set being obtained in a different laboratory and/or with a different method of measurement. The values are traceable to the SI (Système International d'Unités) via calibration using pure substances of known stoichiometry. ³⁾ Estimated expanded uncertainty U with a coverage factor of $k=2$, corresponding to a level of confidence of approx. 95 %, as defined in the Guide to the expression of uncertainty in measurement, ISO, 1993.		

Informative Values		
	Informative value	$s^{1)}$
Element	Mass fraction in mg/kg	
B	< 1.5	
Co	< 1.5	
Li	1.00	0.03
¹⁾ No homogeneity data available, s is the standard deviation calculated from the means of accepted data sets from the certification interlaboratory comparison.		

MEANS OF ACCEPTED DATA SETS

Certified values

Mass fraction in %

Mass fraction in mg/kg

Indicative and informative values

Mass fraction in mg/kg

Line no.	Si	Fe	Cu	Mn	Mg	Ni	Zn	Ti	Cr	Be	Bi	Cd	Ga	Pb	Sr	V	Zr	Ag	Ca	Hg	Sb	Sn	B	Co	Li
1	---	0.1024	0.0290	0.1958	0.0434	0.0217	0.0585	0.0766	57.1	2.65	131	19.6	101	78.7	250	88	31.7	166	10.2	28.9	43.0	87	0.88	0.32	0.97
2	11.91	0.1025	0.0291	0.2004	0.0447	0.0219	0.0597	0.0776	57.8	2.72	131	20.1	102	85.1	261	91	32.4	182	10.8	30.5	49.3	91	1.05	1.06	1.00
3	11.98	0.1026	0.0294	0.2006	0.0448	0.0226	0.0599	0.0780	58.1	2.96	132	20.1	103	85.4	261	95	32.6	186	11.0	30.9	55.5	108	< 1	< 1	1.01
4	11.98	0.1039	0.0294	0.2010	0.0449	0.0226	0.0600	0.0782	58.5	3.00	137	20.6	103	85.9	262	95	32.9	190	13.2	37.2	56.1	109	< 1	< 1	1.02
5	11.98	0.1040	0.0295	0.2028	0.0451	0.0227	0.0601	0.0786	58.7	3.00	137	20.7	103	86.1	265	99	33.0	191		45.2	59.5	111			---
6	12.00	0.1045	0.0299	0.2035	0.0451	0.0228	0.0609	0.0788	58.8	3.03	144	21.6	104	87.5	---	102	33.1				59.8	111			
7	12.04	0.1056	0.0301	0.2037	0.0453	0.0238	0.0609	0.0801	59.9	3.10	151	22.0	106	93.0		114	33.1					126			
8		0.1057	0.0311	0.2045	0.0461	0.0246	0.0616	0.0814	61.9	3.14	152	22.1	109	96.0			33.5								
9		0.1077	---	0.2084	0.0475	0.0258	0.0631	0.0817	62.7			---	117												
10		0.1095		0.2097	---	0.0264	0.0635						---												
11		0.1111		0.2135			0.0641																		
M	11.98	0.1054	0.0297	0.2040	0.0452	0.0235	0.0611	0.0790	59.3	2.95	140	20.8	105	87	260	98	32.8	183	11.3	35	56	106	<1.5	<1.5	1.00
s _M	0.05	0.0030	0.0007	0.0050	0.0011	0.0016	0.0018	0.0018	1.9	0.18	9	1.0	5	6	6	9	0.6	11	1.4	7	5	14			0.03
$\bar{s}_i$	0.06	0.0020	0.0010	0.0024	0.0016	0.0013	0.0006	0.0006	1.3	0.05	7	0.4	3	3	6	2.4	0.9	8.4	1.4	1.5	2	4			0.05

The laboratory mean values have been examined statistically to eliminate outlying values. Each laboratory mean consists of at least 4 but usually 8 single values. Where " --- " appears in the table it indicates that an outlying value has been omitted (Grubbs 95 %). " < "-values have not been considered in statistical evaluation.

M : mean of means of data sets

$\bar{s}_i$: mean of standard deviations of data sets under repeatability conditions

s_M : standard deviation of means of data sets

TECHNICAL REPORT

A detailed technical report (in German) describing the analysis procedures and the treatment of the analytical data used to certify ERM®-EB316 is available on request.

ANALYTICAL METHOD USED FOR CERTIFICATION

Element	Line no.	Method
Si	2, 3, 4, 5, 6	ICP-OES, dissolution in NaOH
	7	XRF, reconstitution method
Fe	1	ICP-OES
	2	ICP-MS
	3	Spectrophotometry, 1,10-phenantroline
	4, 5, 7, 8, 10	ICP-OES, dissolution in NaOH
	6, 11	ICP-OES, dissolution in acid
	9	XRF, reconstitution method
Cu	1	ICP-MS
	2	ICP-OES
	3, 5	ICP-OES, dissolution in acid
	4, 6, 7, 8	ICP-OES, dissolution in NaOH
Mn	1	FAAS
	2, 6, 7, 8, 11	ICP-OES, dissolution in NaOH
	3	ICP-OES
	4	ICP-MS
	5, 10	ICP-OES, dissolution in acid
	9	XRF, reconstitution method
Mg	1	XRF, reconstitution method
	2, 9	ICP-OES, dissolution in acid
	3, 6, 7, 8	ICP-OES, dissolution in NaOH
	4	ICP-MS
	5	ICP-OES
Ni	1, 6	ICP-OES, dissolution in acid
	2, 5, 7, 9, 10	ICP-OES, dissolution in NaOH
	3	ICP-OES
	4	ICP-MS
	8	XRF, reconstitution method
Zn	1	NAA
	2	ICP-MS
	3, 6, 10	ICP-OES, dissolution in acid
	4, 7, 8, 9	ICP-OES, dissolution in NaOH
	5	ICP-OES
	11	XRF, reconstitution method
Ti	1, 4, 6, 7, 8	ICP-OES, dissolution in NaOH
	2	ICP-OES
	3	ICP-MS
	5	ICP-OES, dissolution in acid
	9	XRF, reconstitution method
Cr	1, 5	ICP-OES, dissolution in NaOH
	2	NAA
	3	ICP-OES
	4, 7	ICP-MS
	6, 8	ICP-OES, dissolution in acid
Be	1	ICP-OES, dissolution in acid
	2, 4, 5, 7, 8	ICP-OES, dissolution in NaOH
	3	ICP-MS
	6	ICP-OES

Element	Line no.	Method
Bi	1, 4, 6, 7, 8	ICP-OES, dissolution in NaOH
	2	ICP-MS
	3	ICP-OES
	5	ICP-OES, dissolution in acid
Cd	1, 2, 5, 6	ICP-OES, dissolution in NaOH
	3, 4	ICP-OES, dissolution in acid
	7	ICP-MS
	8	ICP-OES
Ga	1, 8	ICP-OES, dissolution in acid
	2, 6, 7	ICP-OES, dissolution in NaOH
	3	ICP-OES
	4, 5	ICP-MS
	9	XRF, reconstitution method
Pb	1, 2	ICP-OES, dissolution in acid
	3, 7, 8	ICP-OES, dissolution in NaOH
	4, 6	ICP-MS
	5	ICP-OES
Sr	1	ICP-OES, dissolution in NaOH
	2, 3	ICP-OES, dissolution in acid
	4	ICP-MS
	5	ICP-OES
V	1, 3	ICP-OES, dissolution in acid
	2	ICP-OES
	4, 5, 6	ICP-OES, dissolution in NaOH
	7	XRF, reconstitution method
Zr	1	ICP-OES
	2	ICP-MS
	3, 4, 6, 7	ICP-OES, dissolution in NaOH
	5, 8	ICP-OES, dissolution in acid
Ag	1	<i>ICP-OES, dissolution in NaOH</i>
	2, 3, 4	<i>ICP-OES, dissolution in acid</i>
	5	<i>ICP-MS</i>
B	1	<i>ICP-OES</i>
	2, 4	<i>ICP-MS</i>
	3	<i>ICP-OES, dissolution in acid</i>
Ca	1	<i>ICP-OES, dissolution in acid</i>
	2	<i>ICP-MS</i>
	3	<i>ICP-OES</i>
	4	<i>ICP-OES, dissolution in NaOH</i>
Co	1	<i>NAA</i>
	2	<i>ICP-OES, dissolution in NaOH</i>
	3	<i>ICP-OES, dissolution in acid</i>
	4	<i>ICP-MS</i>
Hg	1	<i>ICP-OES</i>
	2	<i>ICP-OES, dissolution in NaOH</i>
	3, 4	<i>ICP-MS</i>
	5	<i>NAA</i>

Element	Line no.	Method
Li	1, 3	ICP-MS
	2	ICP-OES, dissolution in acid
	4	ICP-OES
	5	ICP-OES, dissolution in NaOH
Sb	1, 2, 5	ICP-OES, dissolution in NaOH
	3	NAA
	4	ICP-OES
	6	ICP-MS
Sn	1, 4, 7	ICP-OES, dissolution in NaOH
	2, 6	ICP-OES, dissolution in acid
	3	ICP-OES
	5	ICP-MS

Abbreviations:

ICP-OES:	Inductively coupled plasma optical emission spectrometry
ICP-MS:	Inductively coupled plasma mass spectrometry
NAA:	Neutron activation analysis
XRF:	X-ray fluorescence spectrometry

INTENDED USE

The CRM is intended for establishing and checking the calibration of optical emission and X-ray spectrometers (excluding micro-analysis) for the analysis of samples of similar materials.

INSTRUCTIONS FOR USE

Before use, the surface of the material (approx. 0.1 mm) must be prepared by milling or turning on a lathe. An area with a diameter of approx. 10 mm in the centre of the discs should not be used for spark emission spectrometry and if possible not for X-ray spectrometry.

The minimum sample size for wet chemical analysis is 0.5 g.

STORAGE

The material should be stored in a dry and clean environment at room temperature.

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